

<b>Notice of References Cited</b>	Application/Control No. 10/560,517		Applicant(s)/Patent Under Reexamination ALI-HACKL ET AL.	
	Examiner HUY D. NGUYEN		Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0021199 A1	09-2001	Lee et al.	370/503
*	B	US-2002/0077141 A1	06-2002	Hwang et al.	455/522
*	C	US-2003/0064682 A1	04-2003	Iwamura, Mikio	455/13.4
*	D	US-2003/0119452 A1	06-2003	Kim et al.	455/69
*	E	US-2004/0017843 A1	01-2004	Fitton et al.	375/148
*	F	US-2004/0028121 A1	02-2004	Fitton, Michael P.	375/144
*	G	US-2005/0053049 A1	03-2005	Blanz et al.	370/350
*	H	US-6,888,880 B2	05-2005	Lee et al.	375/149
*	I	US-7,295,597 B2	11-2007	Fitton et al.	375/148
*	J	US-7,352,737 B2	04-2008	Blanz et al.	370/350
*	K	US-7,386,032 B2	06-2008	Fitton et al.	375/147
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.